

REMARKS

The Office Action of September 16, 2002 has been received and reviewed. Applicants would like to thank the Examiner for the consideration given to the above-identified application. Additionally, Applicants would like to thank the Examiner for indicating the allowance of claims 3, 5-7, 16-21, 24-33, and 35-42.

Claims 3-10, 16-33, and 35-42 are pending. By this Amendment, claim 4 has been amended. By the action above and the remarks below, reconsideration and allowance of this application are respectfully requested.

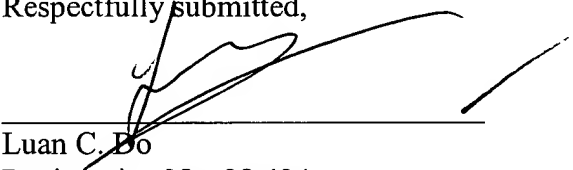
Turning now to the detailed Office Action, claims 4, 8, 9, 22, and 23 stand rejected under 35 U.S.C. §103(a) as unpatentable over Matsumoto (U.S. Patent No. 5,323,042 – hereafter Matsumoto) in view of Ikeda (JP 7-326767 – hereafter Ikeda). Further, claims 4, 8, 10, and 23 stand rejected under 35 U.S.C. §103(a) as unpatentable over Yeo (U.S. Patent No. 6,140,162 – hereafter Yeo) in view of Ikeda, and claim 10 stands rejected as obvious based on Official Notice taken by the Examiner.

As amended, independent claim 4 recites an allowable feature wherein the thickness of the gate insulating film of the TFT in said driver circuit portion is thinner than that of the gate insulating film of a TFT in the pixel portion. This feature is found in the allowed claims and is supported at least in, e.g., page 9, lines 16-21 of the specification. Applicants respectfully submit that this feature is not disclosed, taught, or suggested in the cited prior art references, and, as amended, independent claim 4, as well as its dependent claims 8-10 and 22-23, are distinguishable over the cited prior references.

At this point, Applicants would like to request the Examiner to consider and initial the U.S. Patent references submitted in the IDS dated September 4, 2001, as Applicants have not received back from the Examiner a copy of the Form PTO-1449 initialed to acknowledge consideration therefore.

In view of the above, it is submitted that claims 4, 8-10, and 22-23 are now in condition for allowance. An early and favorable Notice of Allowance is respectfully solicited. In the event that the Examiner is of the opinion that a brief telephone or personal interview will facilitate allowance of one or more of the above claims, the Examiner is courteously requested to contact Applicant's undersigned representative.

Respectfully submitted,



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MARKED UP VERSION

Please amend claim 4 as follows:

4. (Amended) A display device comprising a pixel portion and a driver circuit portion on a substrate, said pixel portion comprising:

a semiconductor film comprising a plurality of channel forming regions, a plurality of impurity regions, a source region, and a drain region; and

a gate electrode overlapping with the channel forming regions and some of the impurity regions, with a gate insulating film interposed therebetween,

wherein said some of the impurity regions are located between the plurality of channel regions in the semiconductor film, [and]

wherein a gate insulating film of a TFT in said driver circuit portion and a dielectric of a storage capacitor formed in said pixel portion comprise the same material and have the same film thickness, and

wherein the thickness of the gate insulating film of the TFT in said driver circuit portion is thinner than that of the gate insulating film of a TFT in the pixel portion.